
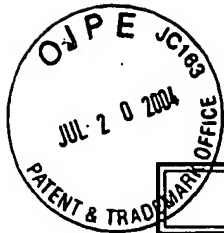


TRANSMITTAL

Electronic Version v1.1

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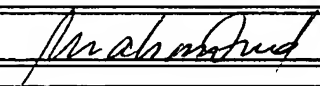
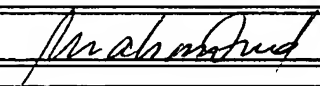
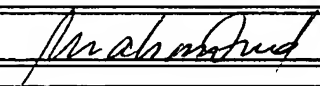
Title of Invention	METHOD FOR CONTROLLING A PROCESS FOR FABRICATING INTEGRATED DEVICES									
<p>Application Number: 10/805136 </p> <p>Date: 2004-03-19</p> <p>First Named Applicant: Matthew F Davis</p> <p>Confirmation Number: 8916</p> <p>Attorney Docket Number: 8381/ETCH</p>										
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<table border="1"><thead><tr><th>Submitted by:</th><th>Elec. Sign.</th><th>Sign. Capacity</th></tr></thead><tbody><tr><td>Keith P Taboada Registered Number: 45150</td><td>/Keith P Taboada/</td><td>Attorney</td></tr></tbody></table>			Submitted by:	Elec. Sign.	Sign. Capacity	Keith P Taboada Registered Number: 45150	/Keith P Taboada/	Attorney		
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<table><tr><td>Documents being submitted</td><td>Files</td></tr><tr><td>us-ids</td><td>APPM8381-usidst.xml</td></tr><tr><td></td><td>us-ids.dtd</td></tr><tr><td></td><td>us-ids.xsl</td></tr></table>			Documents being submitted	Files	us-ids	APPM8381-usidst.xml		us-ids.dtd		us-ids.xsl
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us-ids	APPM8381-usidst.xml									
	us-ids.dtd									
	us-ids.xsl									
Comments <i>final</i> <i>2/2/06</i>										



ELECTRONIC INFORMATION DISCLOSURE STATEMENT

Electronic Version v18

Stylesheet Version v18.0

Title of Invention	METHOD FOR CONTROLLING A PROCESS FOR FABRICATING INTEGRATED DEVICES																				
<p>Application Number: 10/805136 </p> <p>Confirmation Number: 8916</p> <p>First Named Applicant: Matthew Davis</p> <p>Attorney Docket Number: 8381/ETCH</p> <p>Search string: (6566025).pn.</p> <p>US Patent Documents</p> <p>Note: Applicant is not required to submit a paper copy of cited US Patent Documents</p> <table border="1"><thead><tr><th>init</th><th>Cite.No.</th><th>Patent No.</th><th>Date</th><th>Patentee</th><th>Kind</th><th>Class</th><th>Subclass</th></tr></thead><tbody><tr><td></td><td>1</td><td>6566025</td><td>2003-05-20</td><td>McStravick et al.</td><td>B1</td><td></td><td></td></tr></tbody></table> <p>Signature</p> <table border="1"><thead><tr><th>Examiner Name</th><th>Date</th></tr></thead><tbody><tr><td></td><td>2/2/06</td></tr></tbody></table>		init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass		1	6566025	2003-05-20	McStravick et al.	B1			Examiner Name	Date		2/2/06
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U.S. Department of Commerce, Patent and Trademark Office (PTO Form 1449 modified)				Docket No. 8381/ETCH/SILICON/JB1		Serial No. 10/805,136	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT				Applicant Davis, et al.		Confirmation No.: 8916	
(Use several sheets if necessary)				Filing Date March 19, 2004		Group	
Examiner							

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U.S. Patent Documents							
*Examiner Initial		Document Number	Issue Date	Applicant(s) Name	Class	Subclass	Filing Date If Appropriate
<i>jun</i>	A1	4,767,496	08/30/1988	Hieber	156	627	
<i>jun</i>	A2	5,798,529	08/25/1998	Wagner	250	492.2	
<i>jun</i>	A3	5,926,690	07/20/1999	Toprac et al.	438	17	
<i>jun</i>	A4	5,948,203	09/07/1999	Wang	156	345	
<i>jun</i>	A5	6,004,706	12/21/1999	Ausschnitt et al.	430	30	
<i>jun</i>	A6	6,027,842	02/22/2000	Ausschnitt et al.	430	30	
<i>jun</i>	A7	6,161,054	12/12/2000	Rosenthal et al.	700	121	
<i>jun</i>	A8	6,245,581	06/12/2001	Bonser et al.	438	8	
<i>jun</i>	A9	6,424,417	07/23/2002	Cohen et al.	356	388	
<i>jun</i>	A10	6,486,492	11/26/2002	Su	257	48	
<i>jun</i>	A11	2002/0171828	11/21/2002	Cohen et al.	356	328	07/01/2002

Foreign Patent Documents							
*Examiner Initial		Document Number	Date	Country	Class	Subclass	Translation
							YES NO
	B1						<input type="checkbox"/> <input type="checkbox"/>
	B2						<input type="checkbox"/> <input type="checkbox"/>

OTHER ART	
*Examiner Initial	Including Author, Title, Date, Pertinent Pages, Etc.
<i>jun</i>	C1 Lee, et al., "Analysis of Reflectometry and Ellipsometry Data from Patterned Structures," Characterization and Metrology for UCSI Technology: 1998 International Conference, Seiler, et al., eds., pg 331-335
<i>jun</i>	C2 Raymond, "Angle-resolved scatterometry for semiconductor manufacture," Microolithography World, Winter 2000.
<i>jun</i>	C3 Toprac, A., "AMD's Advanced Process Control of Ply-Gate Critical Dimension," Proc. SPIE Vol 3882, pg 62-65, Sept, 1999.
<i>jun</i>	C4 Yang, et al., "Line-profile and Critical Dimension Measurements Using a Normal Incidence Optical Metrology System," Proceedings of SPIE Vol. 4689, March 2002,
Examiner	Date Considered 2/2/05

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.